



T-52-09

August 1991

100323•100323A Low Power Hex Bus Driver

General Description

The 100323 is a monolithic device containing six bus drivers capable of driving terminated lines with terminations as low as 25Ω. To reduce crosstalk, each output has its own respective ground connection. Transition times were designed to be longer than on other F100K devices. The driver itself performs the positive logic AND of a data input (D₁–D₆) and the OR of two select inputs (E and either DE₁, DE₂, or DE₃). Enabling of data is possible in multiples of two, i.e., 2, 4 or all 6 paths. All inputs have 50 kΩ pull-down resistors.

The output voltage LOW level is designed to be more negative than normal ECL outputs (cut off state). This allows an emitter-follower output transistor to turn off when the termi-

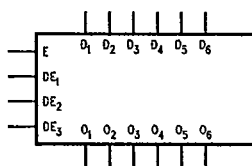
nation supply is –2.0V and thus present a high impedance to the data bus.

NOTE: All information for the 100323A is ADVANCED INFORMATION.

Features

- 50% power reduction of the 100123
- 2000V ESD protection
- –4.2V to –5.7V operating range
- Drives 25Ω load
- Available to industrial grade temperature range
- Tighter AC specifications available on the 100323A

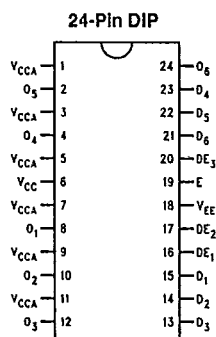
Logic Symbol



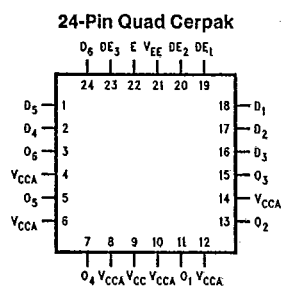
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Pin Names	Description
D ₁ –D ₆	Data Inputs
DE ₁ –DE ₃	Dual Enable Inputs
E	Common Enable Input
O ₁ –O ₆	Data Outputs

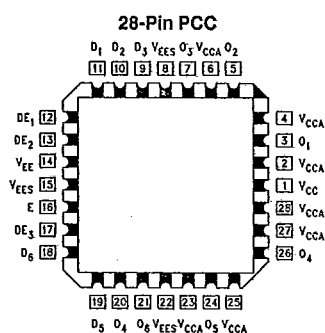
Connection Diagrams



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TL/F/9877-4

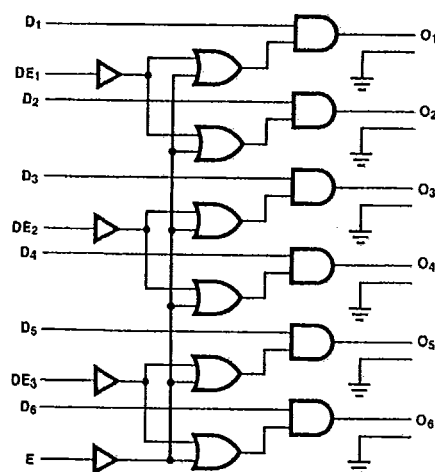


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9000-2720

Logic Diagram

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TL/F/9877-1

Truth Table

E	DE _n	D _n	D _{n+1}	O _n	O _{n+1}
L	L	X	X	Cutoff	Cutoff
X	H	L	L	Cutoff	Cutoff
X	H	L	H	Cutoff	H
X	H	H	L	H	Cutoff
X	H	H	H	H	H
H	X	L	L	Cutoff	Cutoff
H	X	L	H	Cutoff	H
H	X	H	L	H	Cutoff
H	X	H	H	H	H

H = High
Cutoff = Lower-than-LOW state
L = Low
X = Don't Care

Absolute Maximum Ratings (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Storage Temperature	-65°C to +150°C
Maximum Junction Temperature	
Ceramic	+175°C
Plastic	+150°C
V _{EE} Pin Potential to Ground Pin	-7.0V to +0.5V
Input Voltage (DC)	V _{EE} to +0.5V
Output Current (DC Output High)	-50 mA
ESD Last Passing Voltage (Min)	2000V

Recommended Operating Conditions

Case Temperature	
Commercial	0°C to +85°C
Industrial	-40°C to +85°C
Military	-55°C to +125°C
Supply Voltage (V _{EE})	-5.7V to -4.2V

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Commercial Version—100323**DC Electrical Characteristics**V_{EE} = -4.2V to -5.7V, V_{CC} = V_{CCA} = GND, T_C = 0°C to +85°C (Note 3)

Symbol	Parameter	Min	Typ	Max	Units	Conditions
V _{IH}	Input HIGH Voltage	-1165		-870	mV	Guaranteed High Signal for ALL Inputs
V _{IL}	Input LOW Voltage	-1830		-1475	mV	Guaranteed Low Signal for ALL Inputs
V _{OH}	Output HIGH Voltage	-1025	-955	-870	mV	V _{IN} = V _{IH} (max) or V _{IL} (min) Loading with 25Ω to -2.0V
V _{OHc}	Output HIGH Voltage	-1035			mV	V _{IN} = V _{IH} (min) or V _{IL} (max) Loading with 25Ω to -2.0V
V _{OLZ}	Cut-Off LOW Voltage			-1950	mV	V _{IN} = V _{IH} (min) or V _{IL} (max) Loading with 25Ω to -2.0V
I _{IL}	Input LOW Current	0.50			μA	V _{IN} = V _{IL} (min)
I _{IH}	Input HIGH Current			240	μA	V _{IN} = V _{IH} (max)
I _{EE}	Power Supply Current	-121	-91	-57	mA	Inputs Open

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: ESD testing conforms to MIL-STD-883, Method 3015.

Note 3: The specified limits represent "worst case" values for the parameter. Since these values normally occur at the temperature extremes, additional noise immunity and guardbanding can be achieved by decreasing the allowable system operating ranges. Conditions for testing shown in the tables are chosen to guarantee operation under "worst case" conditions.

Dual-In-Line Package AC Electrical CharacteristicsV_{EE} = -4.2V to -5.7V, V_{CC} = V_{CCA} = GND

Symbol	Parameter	T _C = 0°C		T _C = +25°C		T _C = +85°C		Units	Conditions
		Min	Max	Min	Max	Min	Max		
t _{PZH}	Propagation Delay	1.90	3.60	1.90	3.60	2.00	3.80	ns	Figures 1 and 2
t _{PHZ}	Data to Output	1.30	2.70	1.30	2.70	1.50	2.70		
t _{PZH}	Propagation Delay	1.90	3.60	1.90	3.60	2.00	3.90		
t _{PHZ}	Dual Enable to Output	1.60	3.00	1.60	3.00	1.70	3.40		
t _{PZH}	Propagation Delay	1.80	3.50	1.80	3.50	2.00	3.80		
t _{PHZ}	Common Enable to Output	1.50	2.90	1.50	2.90	1.60	3.00	ns	
t _{TZH}	Transition Time	0.50	1.80	0.50	1.80	0.50	1.80	ns	
t _{THZ}	20% to 80%, 80% to 20%	0.35	1.40	0.35	1.40	0.35	1.40		

Commercial Version—100323 (Continued)

PCC and Cerpak AC Electrical Characteristics

 $V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$

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Symbol	Parameter	$T_C = 0^\circ C$		$T_C = +25^\circ C$		$T_C = +85^\circ C$		Units	Conditions
		Min	Max	Min	Max	Min	Max		
t_{PZH} t_{PHZ}	Propagation Delay Data to Output	1.90 1.30	3.40 2.50	1.90 1.30	3.40 2.50	2.00 1.50	3.60 2.70	ns	Figures 1 and 2
t_{PZH} t_{PHZ}	Propagation Delay Dual Enable to Output	1.90 1.60	3.40 2.80	1.90 1.60	3.40 2.80	2.00 1.70	3.70 3.00	ns	
t_{PZH} t_{PHZ}	Propagation Delay Common Enable to Output	1.80 1.50	3.30 2.70	1.80 1.50	3.30 2.70	2.00 1.60	3.60 2.80	ns	
t_{TZH} t_{THZ}	Transition Time 20% to 80%, 80% to 20%	0.50 0.35	1.70 1.30	0.50 0.35	1.70 1.20	0.50 0.35	1.70 1.30	ns	

Note: The specified limits represent the value for the parameter. Since these values normally occur at the temperature extremes, additional noise immunity and guard banding can be achieved by decreasing the allowable system operating ranges. Conditions for testing shown in the tables are chosen to guarantee operation under "worst case" conditions.

Commercial Version—100323A

PCC AC Electrical Characteristics

 $V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = 0^\circ C$		$T_C = +25^\circ C$		$T_C = +85^\circ C$		Units	Conditions
		Min	Max	Min	Max	Min	Max		
t_{PZH} t_{PHZ}	Propagation Delay Data to Output								
t_{PZH} t_{PHZ}	Propagation Delay Data Enable to Output								
t_{PZH} t_{PHZ}	Propagation Delay Common Enable to Output								
t_{TZH} t_{THZ}	Transition Time 20% to 80%, 80% to 20%								
t_{SG-G}	Skew, Gate to Gate								

Industrial Version—100323—Preliminary

DC Electrical Characteristics

 $V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$, $T_C = -40^\circ C$ to $+85^\circ C$ (Note 1)

Symbol	Parameter	$T_C = -40^{\circ}C$		$T_C = 0^{\circ}C$ to $+85^{\circ}C$		Units	Conditions	
		Min	Max	Min	Max			
V_{IH}	Input HIGH Voltage	-1165	-870	-1165	-870	mV	Guaranteed High Signal for All Inputs	
V_{IL}	Input LOW Voltage	-1830	-1475	-1830	-1475	mV	Guaranteed Low Signal for All Inputs	
V_{OH}	Output HIGH Voltage	-1085	-870	-1025	-870	mV	$V_{IN} = V_{IH} (max)$ or $V_{IL} (min)$	Loading with 25Ω to $-2.0V$
V_{OHC}	Output HIGH Voltage	-1095		-1035		mV	$V_{IN} = V_{IH} (min)$ or $V_{IL} (max)$	Loading with 25Ω to $-2.0V$
V_{OLZ}	Cut-Off LOW Voltage		-1900		-1950	mV	$V_{IN} = V_{IH} (min)$ or $V_{IL} (max)$	Loading with 25Ω to $-2.0V$
I_{IL}	Input LOW Current	0.50		0.50		μA	$V_{IN} = V_{IL} (min)$	
I_{IH}	Input HIGH Current		240		240	μA	$V_{IN} = V_{IH} (max)$	
I_{EE}	Power Supply Current	-121	-57	-121	-57	mA	Inputs Open	

Industrial Version—100323—Preliminary (Continued)

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PCC AC Electrical Characteristics

 $V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = -40^\circ C$		$T_C = +25^\circ C$		$T_C = +85^\circ C$		Units	Conditions
		Min	Max	Min	Max	Min	Max		
t_{PZH}	Propagation Delay	1.80	3.40	1.90	3.40	2.00	3.60	ns	Figures 1 and 2
t_{PHZ}	Data to Output	1.20	2.50	1.30	2.50	1.50	2.70		
t_{PZH}	Propagation Delay	1.80	3.40	1.90	3.40	2.00	3.70		
t_{PHZ}	Data Enable to Output	1.50	2.80	1.60	2.80	1.70	3.00		
t_{PZH}	Propagation Delay	1.70	3.30	1.80	3.30	2.00	3.60		
t_{PHZ}	Common Enable to Output	1.40	2.70	1.50	2.70	1.60	2.80		
t_{TZH}	Transition Time	0.40	1.70	0.50	1.70	0.50	1.70	ns	
t_{THZ}	20% to 80%, 80% to 20%	0.25	1.30	0.35	1.20	0.35	1.30		

Note: The specified limits represent the "worst case" value for the parameter. Since these values normally occur at the temperature extremes, additional noise immunity and guardbanding can be achieved by decreasing the allowable system operating ranges. Conditions for testing shown in the tables are chosen to guarantee operation under "worst case" conditions.

Military Version—100323—Preliminary

DC Electrical Characteristics

 $V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$, $T_C = -55^\circ C$ to $+125^\circ C$

Symbol	Parameter	Min	Max	Units	T_C	Conditions	Notes
V_{OH}	Output HIGH Voltage	-1025	-870	mV	$0^\circ C$ to $+125^\circ C$	$V_{IN} = V_{IH}(\max)$	Loading with 25Ω to $-2.0V$ 1, 2, 3
		-1085	-870	mV	$-55^\circ C$	or $V_{IL}(\min)$	
V_{OHC}	Output HIGH Voltage	-1035		mV	$0^\circ C$ to $+125^\circ C$	$V_{IN} = V_{IH}(\min)$	Loading with 25Ω to $-2.0V$ 1, 2, 3
		-1085		mV	$-55^\circ C$	or $V_{IL}(\max)$	
V_{OLC}	Output LOW Voltage		-1610	mV	$0^\circ C$ to $+125^\circ C$	$V_{IN} = V_{IH}(\min)$	Loading with 25Ω to $-2.0V$ 1, 2, 3
			-1555	mV	$-55^\circ C$	or $V_{IL}(\max)$	
V_{OLZ}	Cut-Off LOW Voltage		-1950	mV	$0^\circ C$ to $+125^\circ C$	$V_{IN} = V_{IH}(\min)$	Loading with 25Ω to $-2.0V$ 1, 2, 3
			-1850	mV	$-55^\circ C$	or $V_{IL}(\max)$	
V_{IH}	Input HIGH Voltage	-1165	-870	mV	$-55^\circ C$ to $+125^\circ C$	Guaranteed HIGH Signal for All Inputs	1, 2, 3, 4
V_{IL}	Input LOW Voltage	-1830	-1475	mV	$-55^\circ C$ to $+125^\circ C$	Guaranteed LOW Signal for All Inputs	1, 2, 3, 4
I_{IL}	Input LOW Current	0.50		μA	$-55^\circ C$ to $+125^\circ C$	$V_{EE} = 4.2V$, $V_{IN} = V_{IL}(\min)$	1, 2, 3
I_{IH}	Input HIGH Current		240	μA	$0^\circ C$ to $+125^\circ C$	$V_{EE} = -5.7V$, $V_{IN} = V_{IH}(\max)$	1, 2, 3
			340	μA	$-55^\circ C$		
I_{EE}	Power Supply Current	-145	-55	mA	$-55^\circ C$ to $+125^\circ C$	Inputs Open	1, 2, 3
		-150				$V_{EE} = -4.2V$ to $-4.8V$ $V_{EE} = -4.2V$ to $-5.7V$	

Note 1: F100K 300 Series cold temperature testing is performed by temperature soaking (to guarantee junction temperature equals $-55^\circ C$), then testing immediately without allowing for the junction temperature to stabilize due to heat dissipation after power-up. This provides "cold start" specs which can be considered a worst case condition at cold temperatures.

Note 2: Screen tested 100% on each device at $-55^\circ C$, $+25^\circ C$, and $+125^\circ C$, Subgroups 1, 2, 3, 7, and 8.

Note 3: Sample tested (Method 5005, Table I) on each manufactured lot at $-55^\circ C$, $+25^\circ C$, and $+125^\circ C$, Subgroups A1, 2, 3, 7, and 8.

Note 4: Guaranteed by applying specified input condition and testing V_{OH}/V_{OL} .

Military Version—100323—Preliminary (Continued)

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AC Electrical Characteristics—All Packages

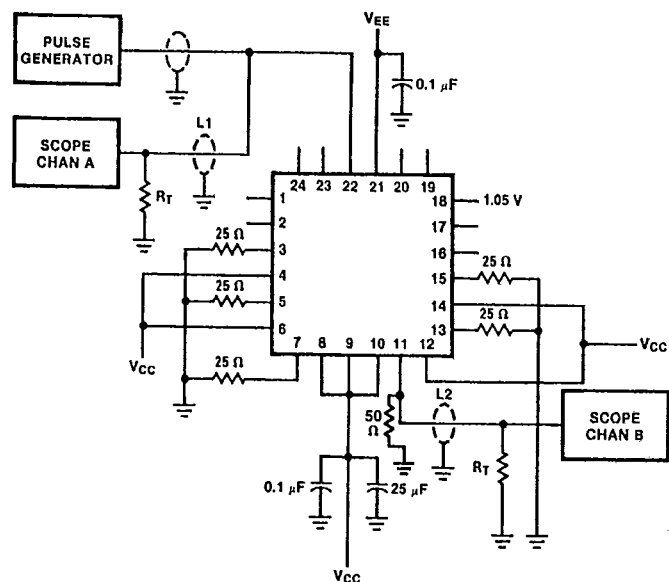
 $V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = -55^\circ C$		$T_C = +25^\circ C$		$T_C = +125^\circ C$		Units	Conditions
		Min	Max	Min	Max	Min	Max		
t_{PZH} t_{PHZ}	Propagation Delay Data to Output	1.70 1.10	4.00 3.10	1.70 1.10	4.00 3.10	1.80 1.30	4.20 3.10	ns	Figures 1 and 2
t_{PZH} t_{PHZ}	Propagation Delay Data Enable to Output	1.70 1.40	4.00 3.40	1.70 1.40	4.00 3.40	1.80 1.50	4.30 3.80	ns	
t_{PZH} t_{PHZ}	Propagation Delay Common Enable to Output	1.60 1.30	3.90 3.30	1.60 1.30	3.90 3.30	1.80 1.40	4.20 3.40	ns	
t_{TZH} t_{THZ}	Transition Time 20% to 80%, 80% to 20%	0.40 0.25	2.20 1.80	0.40 0.25	2.20 1.80	0.40 0.25	2.20 1.80	ns	

Note 1: The specified limits represent the "worst case" value for the parameter. Since these "worst case" values normally occur at the temperature extremes, additional noise immunity and guard banding can be achieved by decreasing the allowable system operating ranges.

Note 2: Conditions for testing shown in the tables are chosen to guarantee operation under "worst case" conditions.

Test Circuitry



Notes:

$V_{CC}, V_{CCA} = +2V$, $V_{EE} = -2.5V$

$L1$ and $L2$ = equal length 50 Ω impedance lines

R_T = 50 Ω terminator internal to scope

Decoupling 0.1 μF from GND to V_{CC} and V_{EE}

All unused outputs are loaded with 25 Ω to GND

C_L = Fixture and stray capacitance ≤ 3 pF

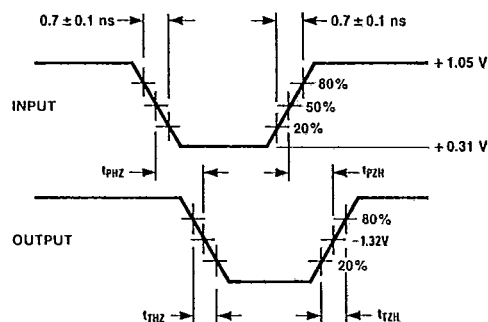
Pin numbers shown are for flatpak; for DIP see logic symbol

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FIGURE 1. AC Test Circuit

Timing Waveform

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FIGURE 2. Propagation Delay and Transition Times

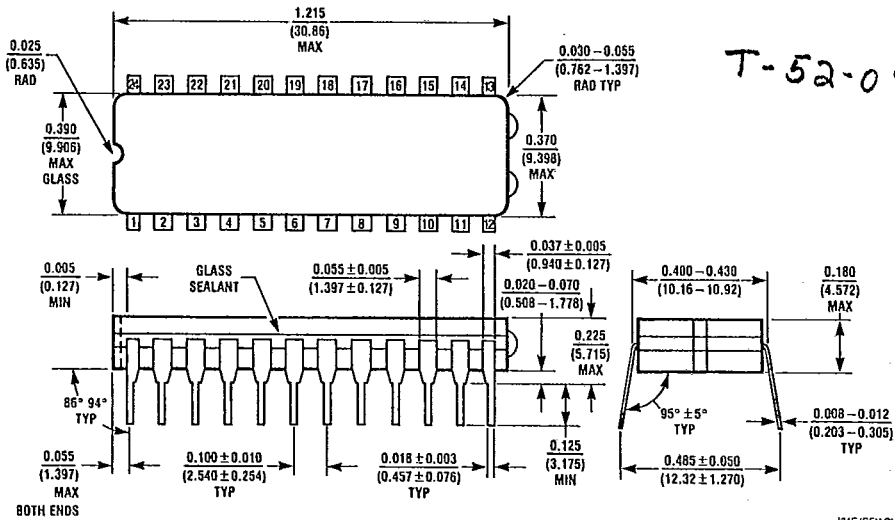
Ordering Information

The device number is used to form part of a simplified purchasing code where a package type and temperature range are defined as follows:

Device Number (Basic)	100323 or 100323A	D	C	QR
Package Code				
D = Ceramic Dual-In-Line				Special Variations
F = Quad Cerpak				QR = Commercial grade device with burn-in
Q = Plastic-Leaded Chip Carrier (PLCC)				QB = Military grade device with environmental and burn-in processing
				Temperature Range
				C = Commercial (0°C to +85°C)
				I = Industrial (-40°C to +85°C) (PCC Only)
				M = Military (-55°C to +125°C)

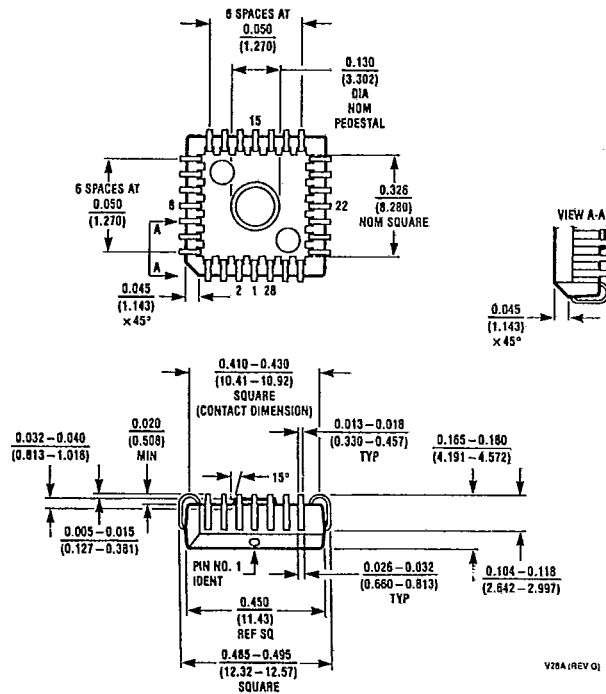
Physical Dimensions inches (millimeters)

NATIONAL SEMICOND (LOGIC)



24 Lead Ceramic Dual-In-Line Package (0.400" Wide) (D)
NS Package Number J24E

J24E (REV D)



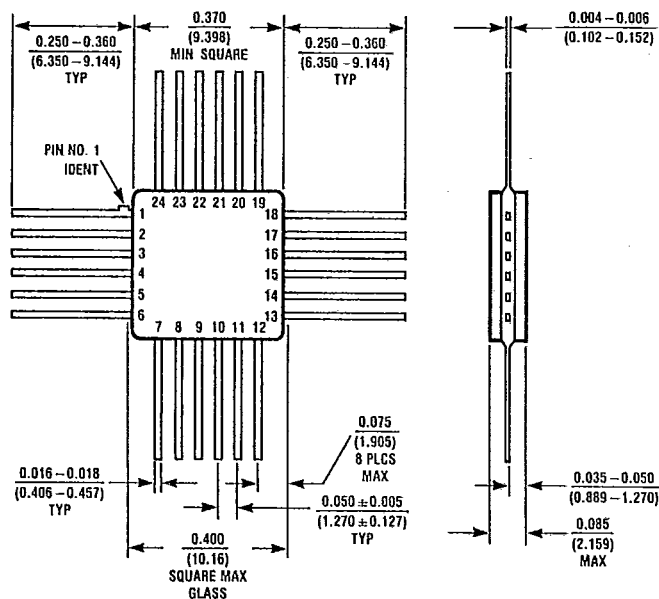
28 Lead Plastic Chip Carrier (Q)
NS Package Number V28A

V28A (REV Q)

Note: Pedestal as shown on base is not available for F100K ECL products.

Physical Dimensions inches (millimeters) (Continued)

Lit. # 114909



W24B (REV C)

24 Lead Quad Cerpak (F)
NS Package Number W24B

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